

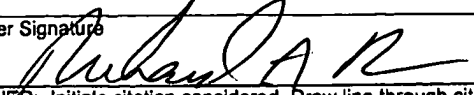
Substitute Form PTO-1449 (Modified)  <b>Information Disclosure Statement                  by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-068001	Application No.
	Applicant Hideto Ohnuma et al.		Group Art Unit
	Filing Date August 10, 2001		

1-5978 U.S. PTO  
 09/925512  
 08/10/01

U.S. Patent Documents							
Examiner Initial	Desig. ID	Patent Number	Issue Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AL							
	AM							
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
<i>RB</i>	AQ	C.W. Kim et al.; "42.1: A Novel Four-Mask-Count Process Architecture for TFT-LCDs"; <u>SID 00 Digest</u> ; pp. 1006-1009; 2000
	AR	
	AS	
	AT	

Examiner Signature 	Date Considered 2/9/04
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Substitute Form PTO-1449 (Modified)  <b>Information Disclosure Statement                  by Applicant</b> (Use several sheets if necessary)  (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 12732-068001	Application No. 09/925,512
	Applicant Hideto Ohnuma et al.		
	Filing Date August 10, 2001	Group Art Unit 2812	

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U.S. Patent Documents							
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	AA						
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							Yes	No
<i>RF</i>	AL	EP 1 003 223	05/24/2000	Europe	H01L	29/786	N/A	
<i>RF</i>	AM	2001-94113	04/06/2001	Japan	H01L	29/786	XX	
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	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
Examiner Initial	Desig. ID	Document
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	AR	
	AS	
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Examiner Signature <i>Richard A. Booth</i>	Date Considered 2/9/04
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